

Laser Fired Emitter on n-type Silicon Using Amorphous Silicon Passivation

A. H. Fischer¹, M. P. Maier^{2,§}, Z. R. Chowdhury¹, G. Hahn², N. P. Kherani^{1,*}, S. Zukotynski¹

¹ University of Toronto, Toronto, Ontario, Canada

² University of Konstanz, Konstanz, Germany

INTRODUCTION

MOTIVATION

- ◆ High conversion efficiency of c-Si photovoltaics
- ◆ Excellent surface passivation using a-Si:H
- ◆ Low-thermal-budget fabrication process
- ◆ Amenable to thinner wafers
- ◆ Simple fabrication process

OBJECTIVES

- ◆ Demonstrate a-Si:H based LFE PV concept using SiO_x isolation layer
- ◆ Perform 2D modeling to evaluate the cell concept
- ◆ Conduct proof of concept experiments

CELL CONCEPT

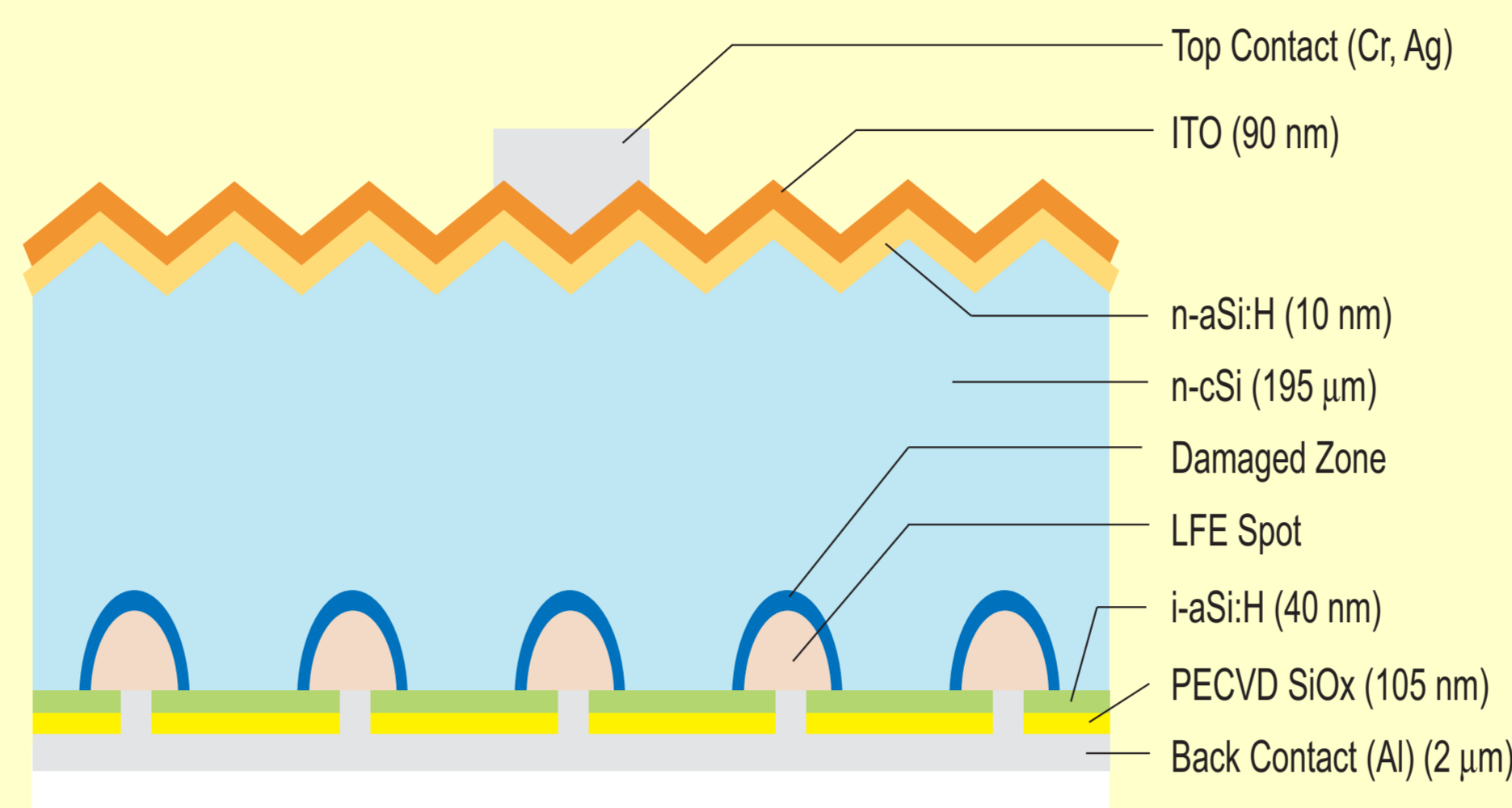


FIG. 1: Schematic of the photovoltaic device with LFE, a-Si:H layers and isolation (oxide) layer.

- ◆ Inverted cell
- ◆ n-type substrate
- ◆ Double-sided hydrogenated amorphous silicon (a-Si:H) passivation
- ◆ PECVD SiO_x Isolation layer
- ◆ Q-Switched Nd:YAG laser fired emitter (LFE)

SIMULATION OF THE CELL

- ◆ 2D modelling using Sentaurus
- ◆ a-Si:H representation with band-tail and band gap defects
- ◆ Lambertian front surface and completely reflective back surface

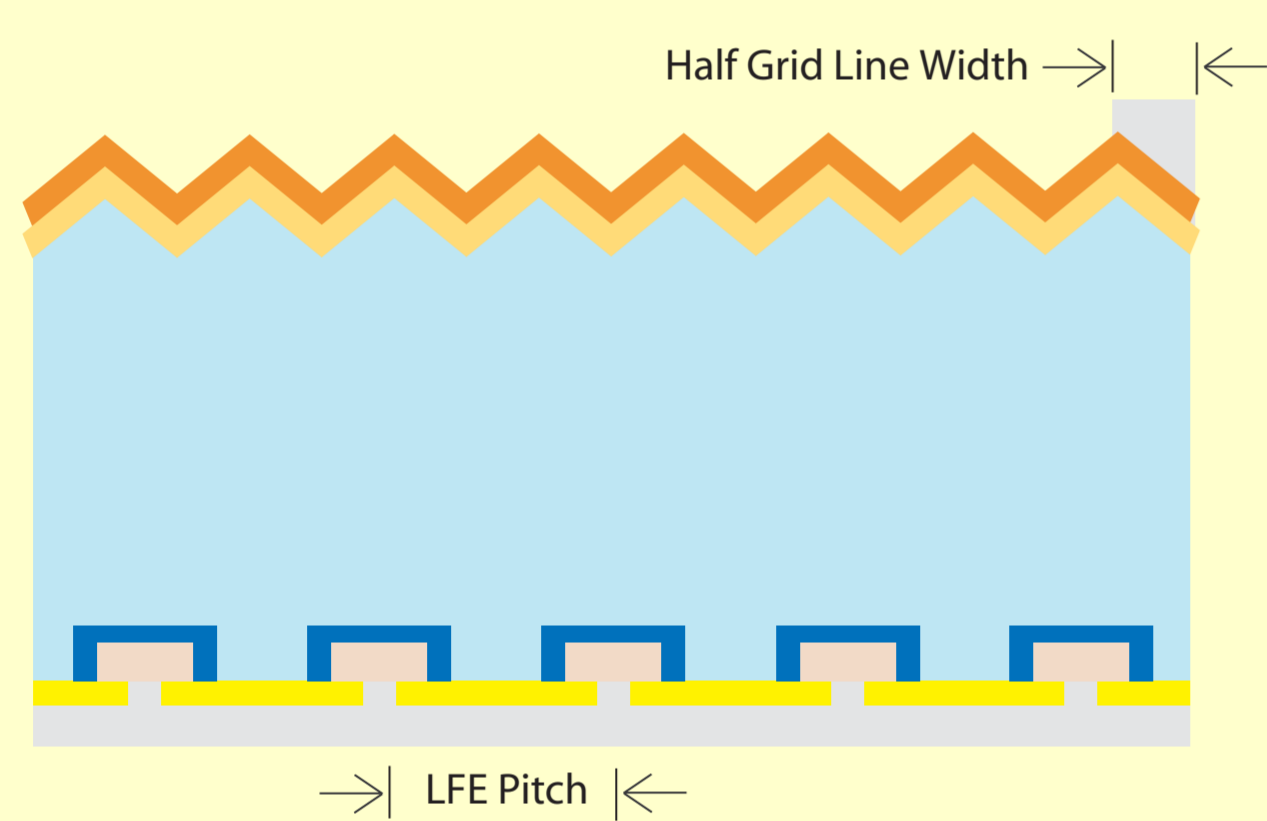


FIG. 2: A unit cell to represent the cell for 2D simulation. Surface passivation at the back is represented by low SRV between c-Si and SiO_x layer

SIMULATION RESULTS

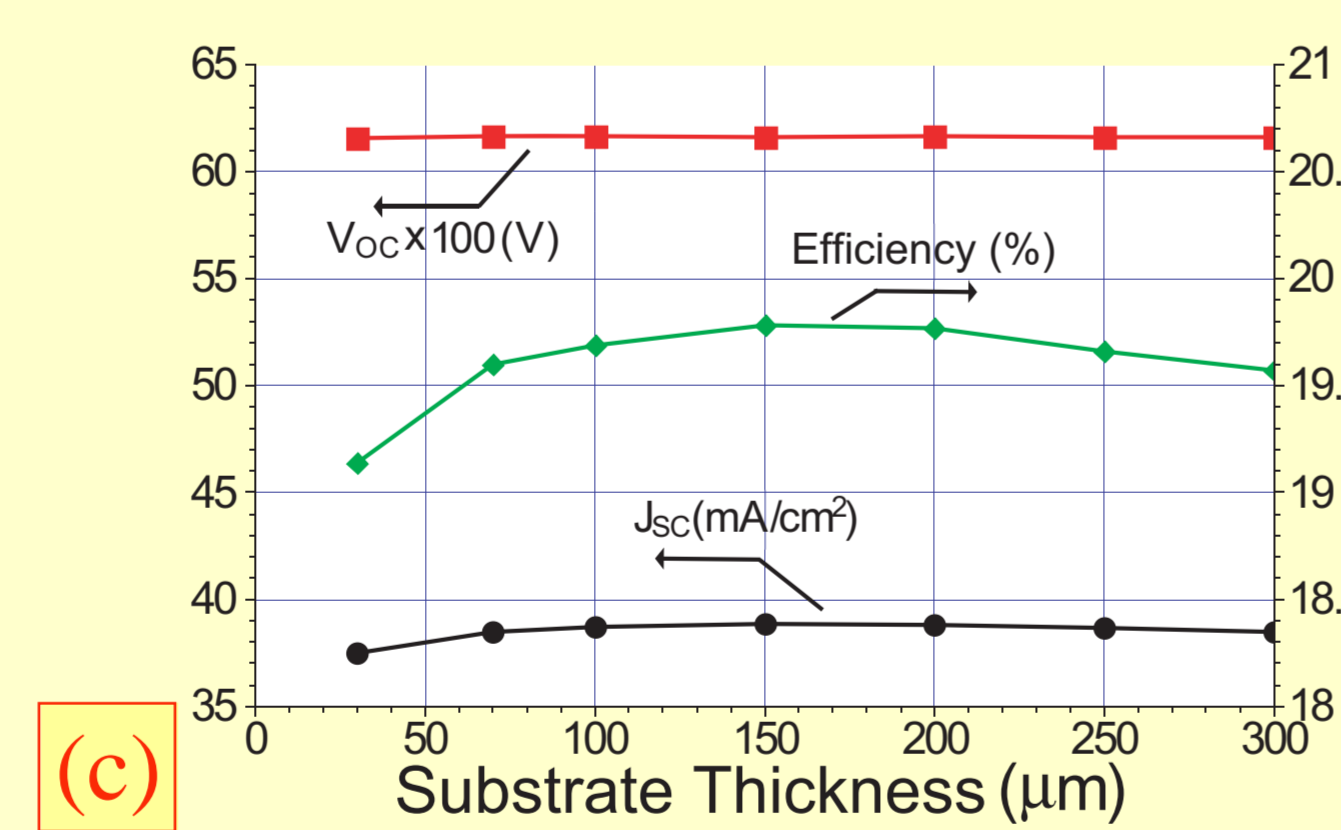
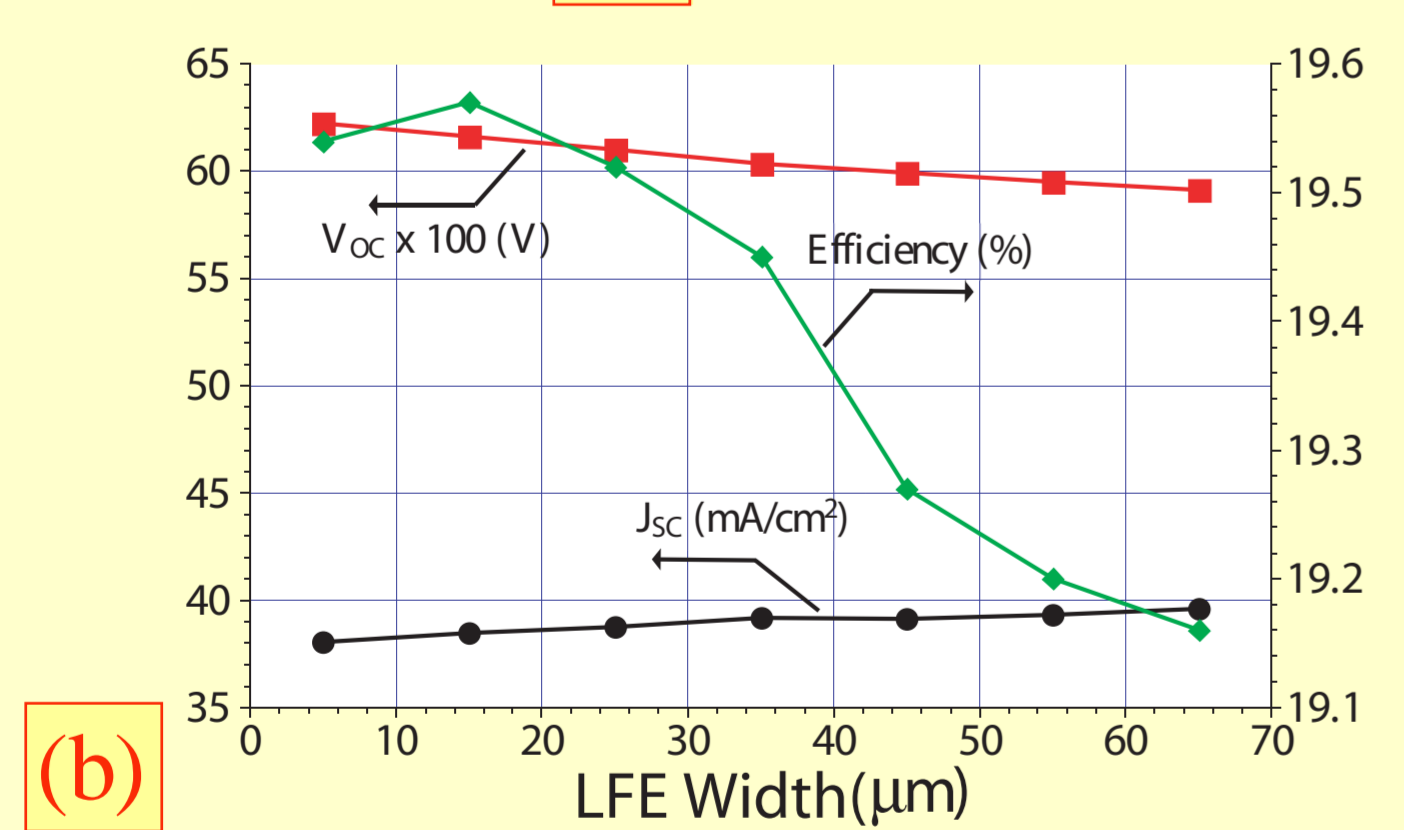
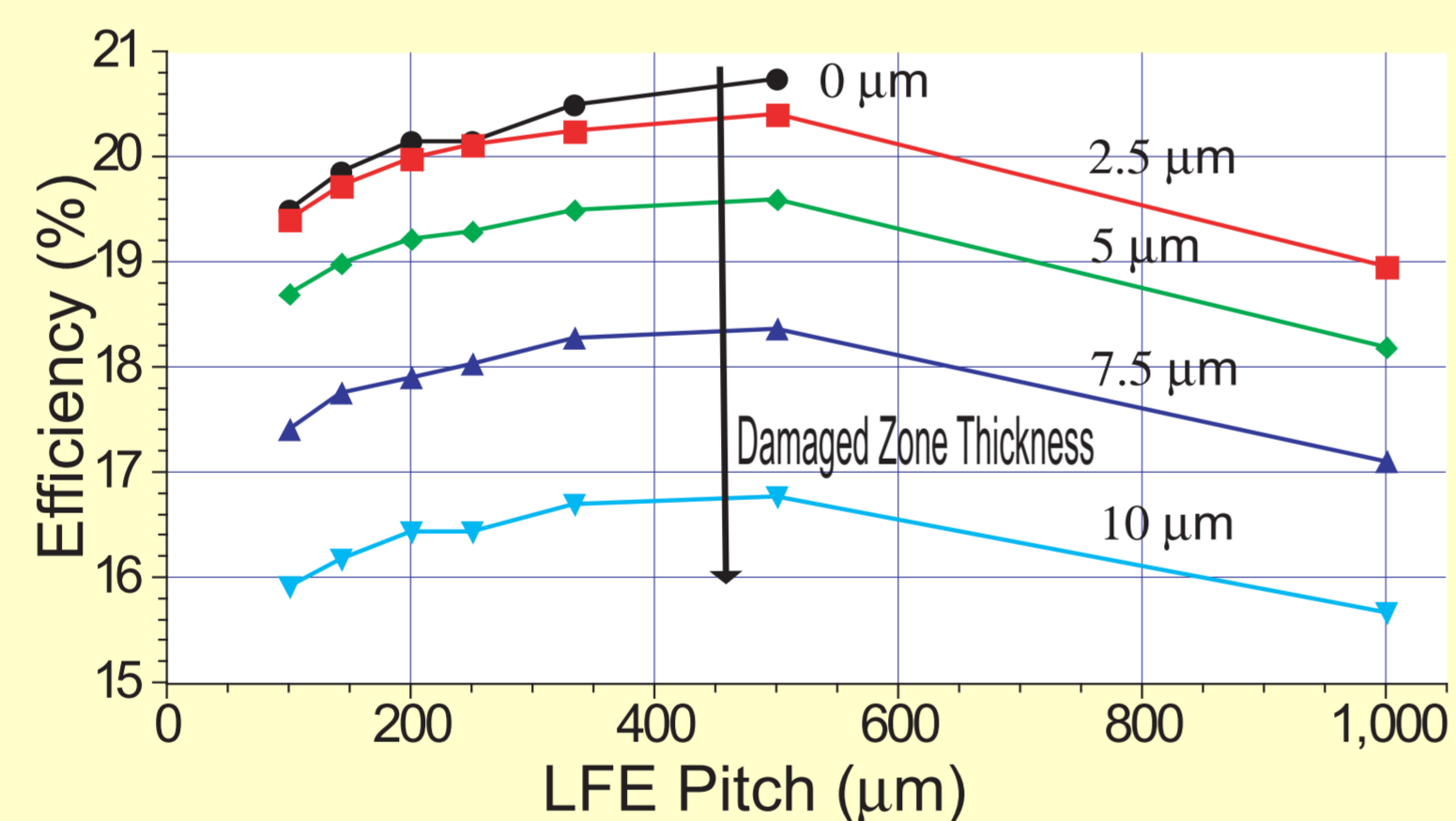


FIG. 3: Performance variation with (a) LFE pitch and damaged spot thickness (b) LFE diameter (c) Substrate thickness

SUMMARY

- ◆ Potential efficiency of 20%
- ◆ The cell structure is suitable for thin wafers
- ◆ Optimal LFE width is 15 μm with 5 μm thick laser-damaged zone

CONCLUSIONS

- ◆ Demonstrated viability of a-Si:H/SiO_x rear stack in an LFE PV device
- ◆ Proof of concept cell efficiency of >11% demonstrated
- ◆ Cell configuration has 20% efficiency potential

PROOF OF CONCEPT

FABRICATION DETAILS

- ◆ Wafer: n-type FZ 20 Ω-cm, (100) orientation
- ◆ DC saddle field for a-Si:H deposition 170° C
- ◆ Ambient atmosphere 240°C anneal after amorphous deposition
- ◆ E-beam metallization
- ◆ Post device fabrication annealing in nitrogen atmosphere

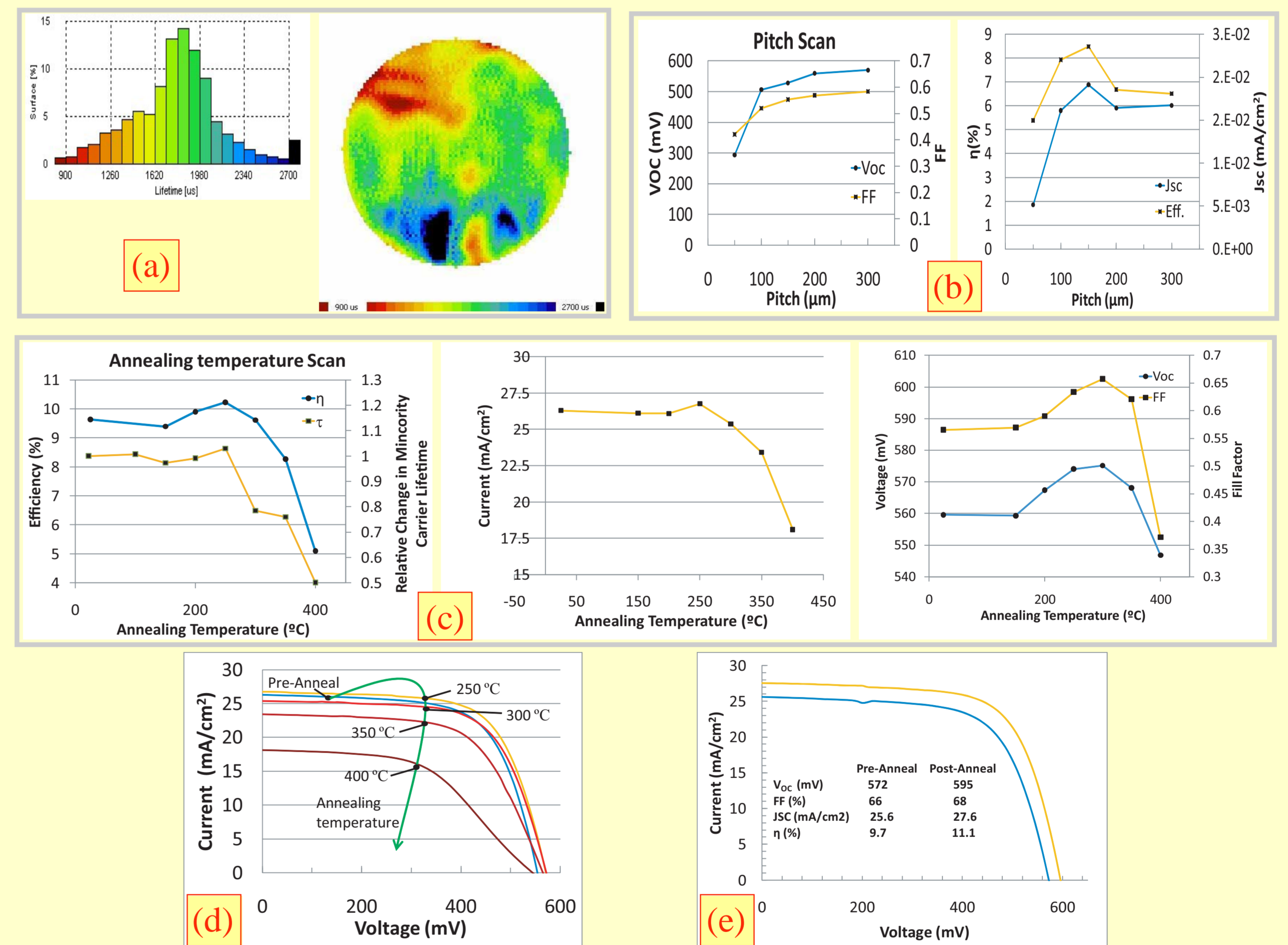


FIG. 4: (a) Life time profile using μ-PCD (b) cell performance variation with LFE pitch (c) cell performance for annealing at different temperature, (d) IV characteristics for different annealing temperature (e) best cell performance after annealing.

SUMMARY

- ◆ Demonstrated cell efficiency of >11%
- ◆ Optimum cell performance found at 150 μm LFE pitch
- ◆ Annealing up to 250°C increases cell performance with minimal lifetime gain, suggesting a mitigation of the laser-damaged zone

References

- Schneiderlochner, E., et al., Laser-fired rear contacts for crystalline silicon solar cells. Progress in Photovoltaics: Research and Applications, 2002. 10 (1): p. 29-34.
- Glunz, S.W., et al. Analysis of laser-fired local back surface fields using n+ np+ cell structures. in Photovoltaic Energy Conversion, 2003. Proceedings of 3rd World Conference on. 2003.
- Granek, F., et al., Optimization of Laser-Fired Aluminum Emitters for High Efficiency N-Type Si Solar Cells, in 21st EU PVSEC. 2006, WIP-Munich: Dresden.
- Hofmann, M., et al., Stack system of PECVD amorphous silicon and PECVD silicon oxide for silicon solar cell rear side passivation. Progress in Photovoltaics: Research and Applications, 2008. 16(6): p. 509-518.
- Munoz, D., et al., Development of LASER fired contacts on silicon heterojunction solar cells for the application to rear contact structures. PhysicaStatus Solidi (C) Current Topics in Solid State Physics, 2010. 7(3-4): p. 1029-1032.